PIP-II Beam Pattern Generator Upgrade

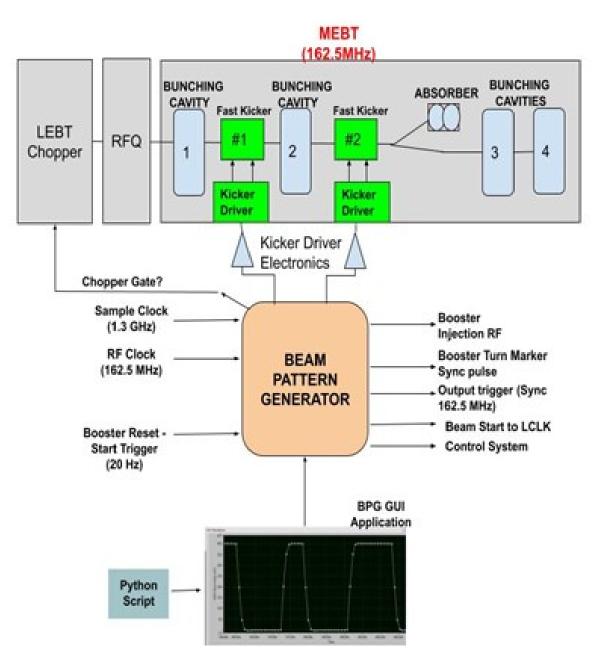
P. Varghese*, H. Shukla, S. Raman, D. Klepec, Fermilab, Batavia, IL, USA J. Dusatko, D. Chabot, SLAC, Menlo Park, CA, USA

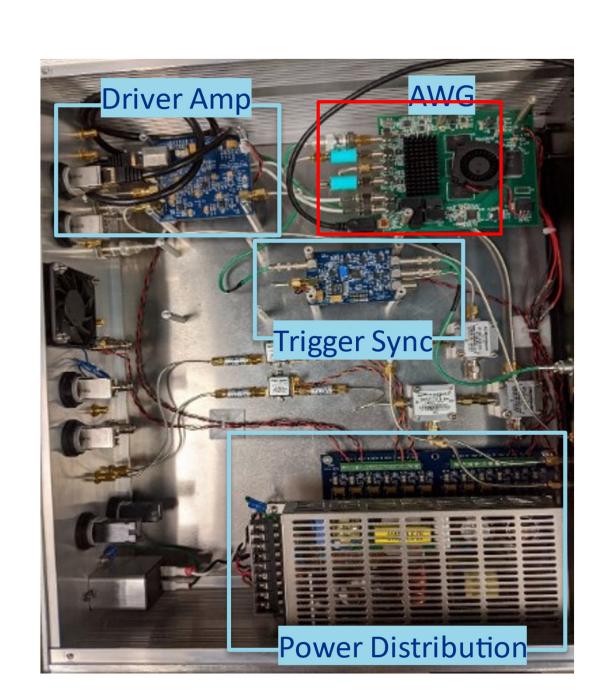
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Introduction

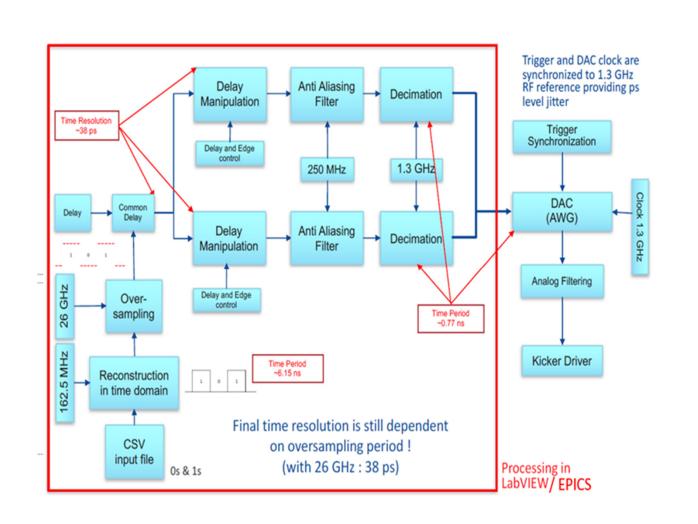
A prototype beam pattern generator for the PIP-II Linac testing used Labview and an external server for the pattern generation. A new design using a COTS sourced SoCFPGA and a DAC board offers the advantages of low hardware and development cost. The pattern generation, digital signal processing and the interface to an external EPICS server are integrated into the ARM processor of the FPGA. The system design is described and the test results are presented.

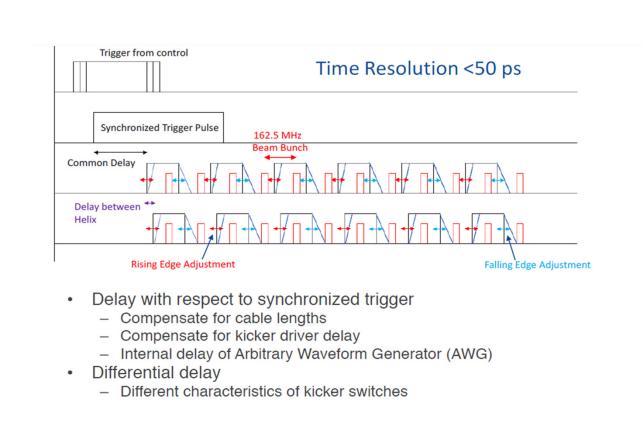
BPG Prototype



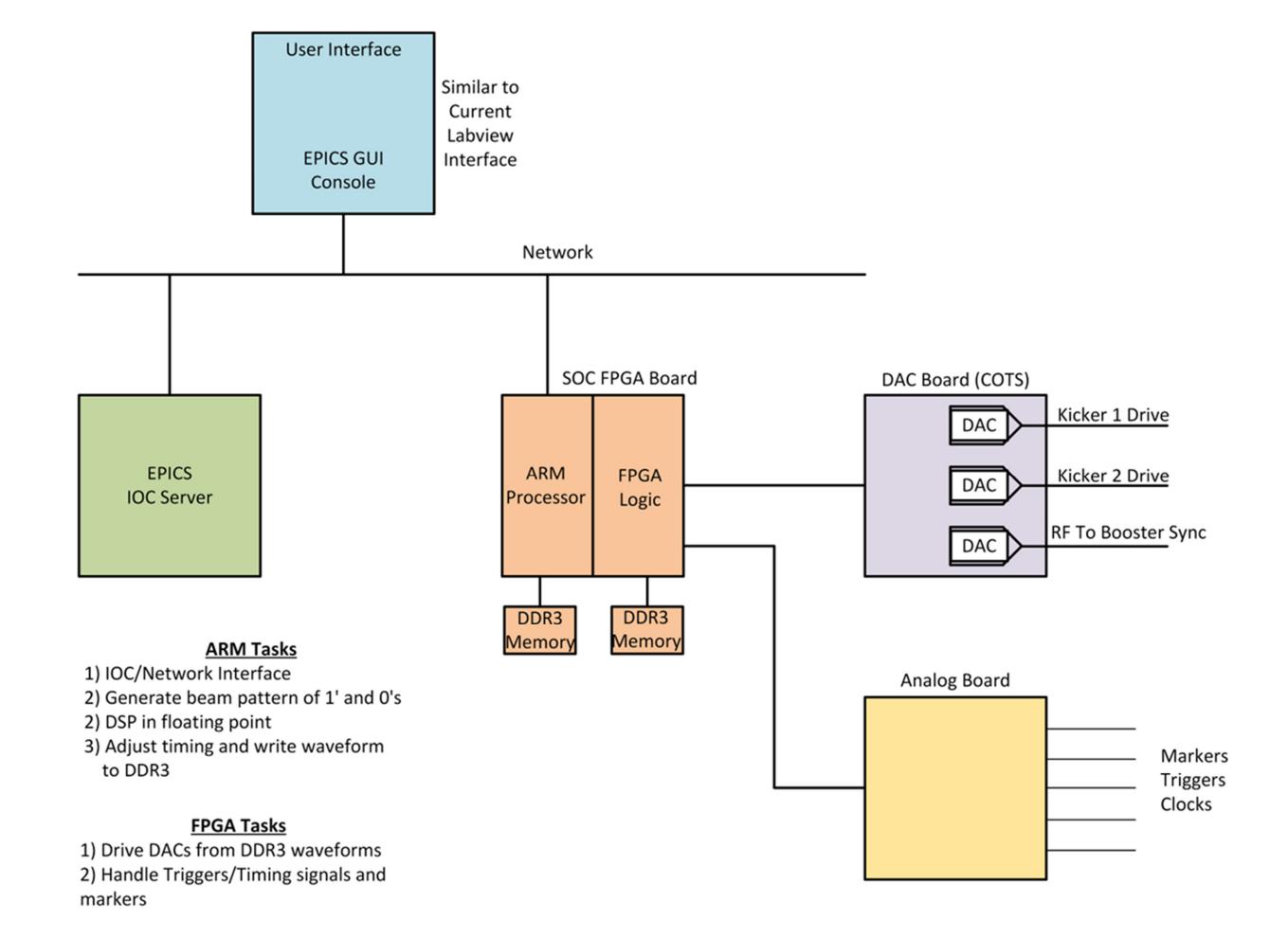


Signal Processing and Delay Adjustment

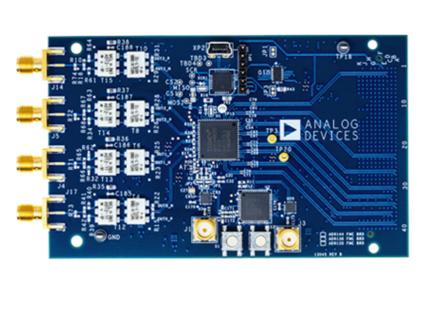




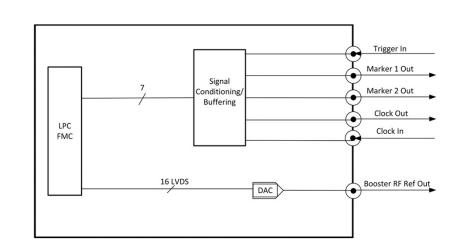
BPG Upgrade Architectuure



Hardware Components





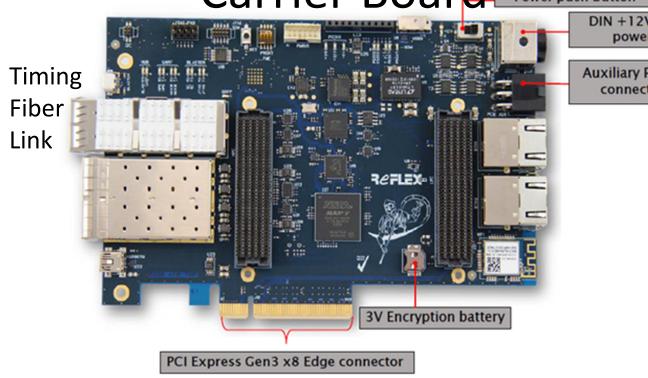


AD9172-FMCEBZ

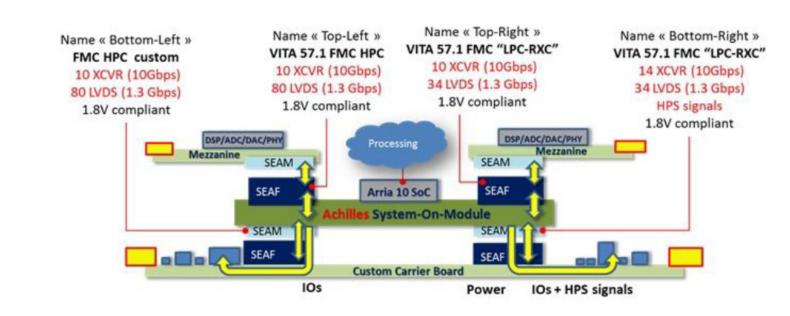
16-bit, 12.6 GSPS, Ext Clk Input

FMC Analog PCB Arria10 SOM

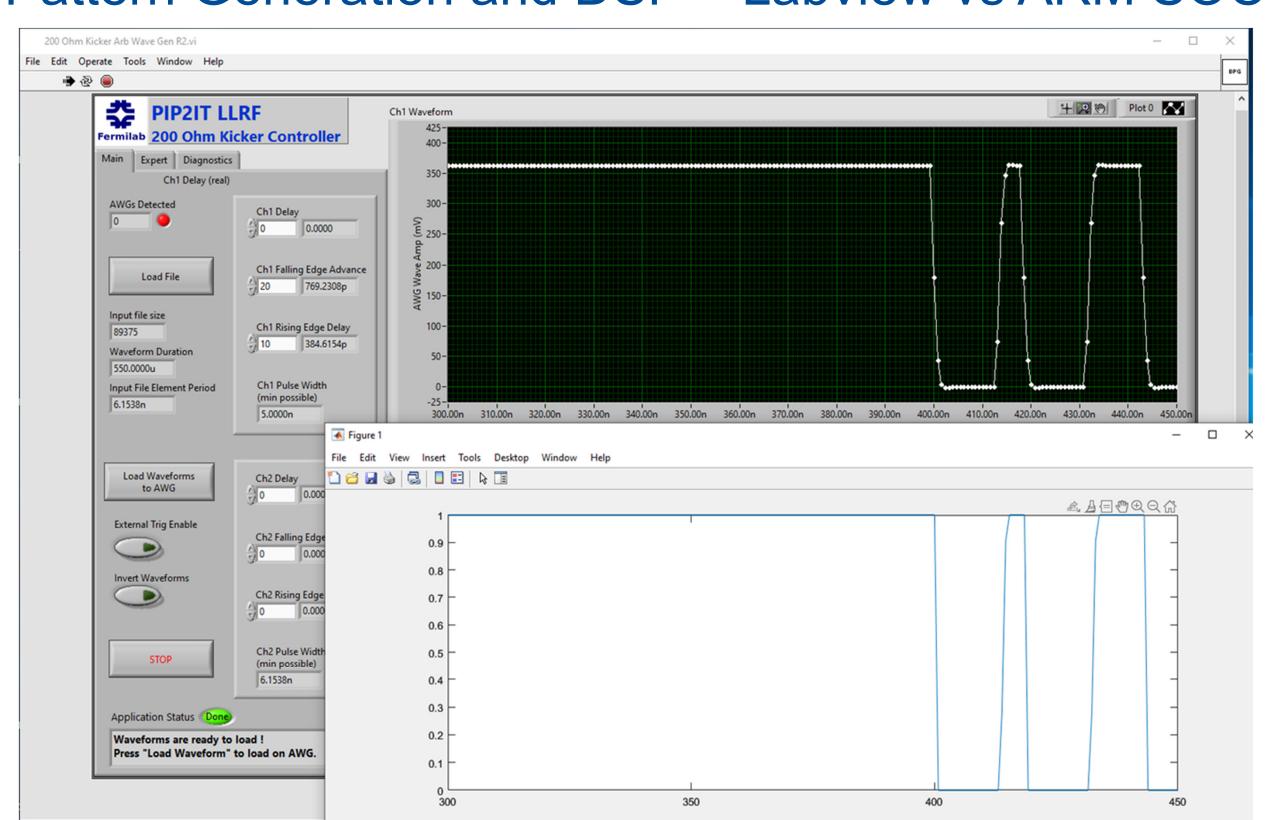
DAC Board – Multiple Choices Carrier Board Power push button



Hardware Configuration



Pattern Generation and DSP – Labview vs ARM SOC



DAC Output Prototype



DAC Output SOCFPGA



Summary

- Major technical aspects for the upgrade already studied and demonstrated to work
- Tested Performance with prototype is guaranteed since the signal processing implemented is the same used at PIP2IT
- This upgrade is a joint project with SLAC







